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Attorney Docket No. 1075.1185

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Takahisa HIRAIDE

Application No.: Unassigned

Group Art Unit: Unassigned

Filed: December 3, 2001

Examiner:



For: TESTING APPARATUS AND TESTING METHOD FOR AN INTEGRATED CIRCUIT,
AND INTEGRATED CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1. Enclosures accompanying this Information Disclosure Statement are:

- 1a. ☒ Form PTO-1449.
- 1b. ☒ Copies of IDS citations.
- 1c. ☐ An English language copy of search report(s) from a counterpart foreign application or a PCT International Search Report.
- 1d. ☐ English language translation (complete or relevant portion(s)) attached to each non-English language publication.
- 1e. ☒ Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.

2. ☒ In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is

(Check appropriate Items 2a, 2b, 2c and/or 2d)

- 2a. ☐ satisfied because all non-English language publications were cited on the enclosed "English-language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, pp. 600-100 to 600-101, Rev. 1, Feb. 2000.)
- 2b. ☐ set forth in the application.

- 2c. ☐ satisfied because an English language translation (complete or relevant portion(s)) is attached to each non-English language publication.
- 2d. ☒ enclosed as Attachment 1(e), hereto.
3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

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PRIOR ART INFORMATION LIST

Your case No.	
Our case No.	FC.560.0052338-US

Inventor, Patent Number, Country, Author, Title, Name of Document	Issue Date (d/m/y)	Concise Explanation of the Relevance (indication of page, column, line, figure of the relevant portion)
a) H. MURAOKA "TEST PATTERN SET COMPRESSOR, METHOD THEREFOR, AND RECORDING MEDIUM," Japanese Patent Laid-Open (Kokai) NO. 2000-329831	30/11/2000	Abstract
b) M. NAKAZAWA "SYSTEM OF AUTOMATICALLY FORMING INSPECTION INPUT," Japanese Patent Laid-Open (Kokai) NO. SHO 61-240173	25/10/1986	Abstract
c) A. TATEISHI "TEST PATTERN GENERATING DEVICE," Japanese Patent Laid-Open (Kokai) NO. SHO 63-83679	14/04/1988	Abstract
d) T. TOUMIYA "CIRCUIT DIVISION ATG PARTIAL CIRCUIT PROCESSING SYSTEM, CIRCUIT DIVISION ATG PARTIAL CIRCUIT PROCESSING METHOD, AND STORAGE MEDIUM WHERE CIRCUIT DIVISION ATG PARTIAL CIRCUIT PROCESSING METHOD IS WRITTEN," Japanese Patent Laid-Open (Kokai) NO. HEI 11-237450	31/08/1999	Abstract
e) D. ULRICH, et al. "METHOD AND APPARATUS FOR TESTING A VLSI DEVICE," Japanese Patent Laid-Open (Kokai) NO. HEI 4-236378	25/08/1992	European Patent Application : Publication NO.0481097 A1 (published on 22/04/1992)
f) K. IZAWA "LSI TEST PATTERN GENERATING PART," Japanese Patent Laid-Open (Kokai) NO. SHO 57-116269	20/07/1982	Abstract

J1046 U.S. PTO

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